

EMC SEMINAR

From Cradle to Grave

Auditorium Denayer

FEE Seminar - 21 juni 2016

Free Registration : www.emcseminar.eu

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Partners:



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PROGRAM

08u30-09u30	Registration - Welcome coffee		
09u30-09u45	Welcome words - Intro Labo Denayer - information concerning parallel sessions (Filip Nauwelaerts - Labo Denayer)		
	STANDARDS & DIRECTIVES (AULA A)	PRACTICAL ASPECTS (AULA B)	VISIT*
09u45-10u15	<p>HFPQ: 2 – 150 kHz, free of standards, but not free of troubles <u>Content:</u> The standards for the 2 to 150 kHz frequency range are still under construction. The lecture gives an insight why compatibility levels are still missing. Additionally an idea of what levels can be expected are presented, based on grid surveys. (Jos Knockaert - Lemcko - UGent)</p>	Mutual Inductance (Paul Lots -Laborelec - GDF Suez)	
10u15-10u45	<p>What about the new Radio Equipment Directive (RED)? (PART 1&2) <u>Content:</u> The high demand for integration of RF modules in electronic end-products still is increasing. Integration of such modules by suppliers can have a significant impact on the certification requirements, since the new Radio Equipment Directive (RED) will come into play. During this presentation, the practical experience on how to tackle these requirements and how they are translated in a company specific strategy for Barco is highlighted. Laboratoria De Nayer will focus on the essentials of RED and what you may expect in terms of the technical content of an actual assessment in the framework of ETSI EN 300 220/330/440 (Dora Deboeure, Barco)</p>	<p>Near Field Measurement -Techniques to Debug EMC Emission Problems <u>Content :</u> Typical EMC measurements at 3, 5 or 10m away from the device-under-test give little insight in the root-cause of emission issues. This presentation describes a generic methodology that allows to efficiently debug EMC emission problems by using a combination of near-field measurement techniques (current probes, hand-held probes,...) (Davy Pissoort - KU Leuven)</p>	
10u45-11u15	<p>Laboratoria De Nayer will focus on the essentials of RED and what you may expect in terms of the technical content of an actual assessment in the framework of ETSI EN 300 220/330/440 (Dora Deboeure, Barco) (Dirk Van Troyen & Filip Nauwelaerts,Labo De Nayer)</p>	<p>Fastest EMC testing by combining dual CISPR detectors with high-speed TD-Scan. <u>Content:</u> Rohde & Schwarz will explain the technology behind it's latest innovation in compliance EMI analysis using high-speed time domain scanning to capture EMI disturbances in less time. Together with dual CISPR detectors operating in parallel and the real-time analysis functionality, test times of a full EMI test cycle can be reduced drastically, thus increasing the efficiency and capacity of test houses (Andy Coombes - Product Manager EMC Test Solutions RS UK)</p>	
11u15-11u45	Contact Opportunities Coffee Break -		
11u45-12u15	<p>10 Golden rules for an efficient RF Interference free design of your apparatus or system. How to deal with undesired Radiated RF Emissions. Minimum formulas, maximum tips (Jos Westhof-Jacobs, W-boost)</p>	<p>Improve throughput of EMC compliance testing with Time Domain Scanning (Daniel Bockstal Acal BFI) <u>Content:</u> Electromagnetic compatibility (EMC) testing requires detailed and exacting methodologies to ensure that all emissions are accurately measured. Long test times impact test facility availability and reduce the number of devices that can be certified. In this presentation time domain scan will be explained and show how it can provides the greatest time savings</p>	

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	STANDARDS & DIRECTIVES (AULA A)	PRACTICAL ASPECTS (AULA B)	VISIT*
12u15-12u45	CISPR 22 -> CISPR 32; A short overview of the differences (Paul Van Bavel - Engineer Prodrive)	Multi-Tone, the next generation of Radiated Immunity testing to save you money, time to market and get closer to real world EMC threats" (AR Benelux) Content: This presentation will provide an introduction to the revolutionary technology which will help you increase the speed of your Radiated Immunity testing, it has been found that this method also improves equipment efficiency, offers greater flexibility to truly test the products (EUT) closer to real world threat conditions. We start with introducing why Radiated Immunity testing is required, what traditional Radiated Immunity testing equipment is and what is required to realise the practical advantages of Multi tone Radiated Immunity testing.	
12u45-13u45	Contact Opportunities - Walking Lunch		
13u45-14u15	An overview on automotive requirements for EMC (Part 1&2) <u>Content:</u> Automotive electronic modules such as aftermarket products often require an EMC assessment according to Regulation 10. In some cases a type approval is required (E-mark). Laboratoria De Nayer and Blue Guide EMC will present an overview on some practical aspects related to type approval with a focus on specific test methods to obtain it. (Dirk Van Troyen & Filip Nauwelaerts, Labo De Nayer)	Practical Approach to EMI Diagnostics Webinar' Content: Learn about the latest test methods for EMI diagnostics and practical theory that will help you approach EMI testing more successfully." (Rick Kundi, Tektronix on behalf of CN Rood)	
14u15 - 14u45	(Ivan Malfait, BGEMC)	News in IEC 61000-4-4 (EFT / Burst immunity test) and IEC 61000-4-5 (Surge immunity test) (Frank Niechcial, Ametek CTS on behalf of Accelonix)	
14u45 - 15u15	Contact Opportunities Coffee Break -		
15u15-15u45	New challenges in Edition 4.0 of the medical EMC standard IEC 60601-1-2 (Wilko De Graaf - Philips Healthcare) <u>Content:</u> IEC 60601-1-2 is a safety-based standard. In the 2014 edition a number of tests were updated to cover the present environment in hospitals, but also in the home healthcare environment. For some immunity tests the test levels are increased, and a new test is introduced to simulate the effects of nearby radiation from wireless devices. The risk management is more emphasized, and gives some room to adapt test levels. For manufacturers the immunity of products is a challenge, besides the risk management. For test laboratories the increased test levels may be a challenge.	Leakage currents in fault-current protected environments Content: To provide for improved protection of operating personnel, residual current operated circuit breakers are seeing increased use in electrical installations. These, however, often trip unnecessarily due to leakage currents caused by electrical systems. The results are machine downtime and costs that can otherwise be prevented with design consideration to high leakage currents and targeted countermeasures. Because frequency inverters and power-line filters are significant causes of ground currents, they deserve special attention. (Herbert Blum, Schurter Product Manager EMC products) (Mark Hammerich, Alcom PLM Power & EMC products)	
15u45-16u15	Hazard based Safety Standard vs ITE 60950 Outcome of a gap analysis (Dora Deboeure, Barco)	EMI Risk Management (Davy Pissoort - KU Leuven) Content : Electronics is being used more and more for safety- or mission-critical applications. Unfortunately, all electronics is becoming increasingly susceptible for EMI. This call for the development of proper "EMI Risk Management", which combines the disciplines EMC and Functional Safety. This presentation shows how to make the bridge between these two disciplines.	
16u15-17u00	Contact Opportunities - Reception		
* During the day possibility to visit Laboratoria De Nayer Product Certification Center			

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EXPOSANTEN



FEE, Federatie van de Elektriciteit en de Elektronica, verenigt en ondersteunt de bedrijven uit de sector van de electriciteit en de electronica, en verdedigt hun belangen. <http://www.feebel.be>

Who should attend?

EMC R&D Engineers, EMC Test Operators, Q&A Managers
Electric Engineers, Development engineers, Technical and
R&D management, Project managers, General Managers,
Professors, Hardware engineers

More Information

For more information and registration on this seminar check
our website <http://www.emcseminar.eu>

Contact

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Free Registration required

Place

Auditorium De Nayer
Jan De Nayerlaan 5, 2860 Sint-Katelijne-Waver

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Bereikbaarheid

Auditorium De Nayer is gemakkelijk te bereiken met de auto of met de trein. Het station is vlak aan het auditorium. Er zijn rechtstreekse treinen vanuit Brussel, Antwerpen en Mechelen.

Bus: 140 m stappen tot de bushalte op de Goorboslei

Trein: 400m stappen tot station Sint-Katelijne-Waver

Wagen: Grote parking aan het auditorium



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